



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Farnworth et al.

Serial No.: 10/669,949

Filed: September 24, 2003

For: WAFER-LEVEL TESTING APPARATUS AND METHOD

Confirmation No.: 4767

Examiner: M. Trinh

Group Art Unit: 2822

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AMENDMENT PURSUANT TO 37 C.F.R. § 1.312(a)

Mail Stop ISSUE FEE
Commissioner for Patents
P.O. Box 1450
Alexandria, Virginia 22313-1450

Sir:

Please amend the above-referenced application as follows:

Amendments to the Specification begin on page 3 of this paper.

Amendments to the Claims are reflected in the listing of claims which begins on page 5 of this paper.